

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	2	"5972475".pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2007/01/03 06:50
L2	1	"5972475".pn.	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 06:50
L10	39	("5241185").URPN.	USPAT	OR	ON	2007/01/03 09:38
L11	16	I10 and (film resist photoresist) near7 (thick thickness height measur\$3 measurement)	USPAT	OR	ON	2007/01/03 09:58
L12	5652	(proximity near2 effect)	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 09:58
L13	1286	(proximity near2 effect) and (film resist photoresist) near7 (thick thickness height)	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 09:59
L14	1208	(proximity near2 effect) and (film resist photoresist) near4 (thick thickness height)	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 09:59
L15	624	(proximity near2 effect) and (film resist photoresist) near7 (thick thickness height) and (e-beam electron near2 beam)	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 10:00
L16	576	(proximity near2 effect) and (film resist photoresist) near7 (thick thickness height) and (e-beam electron near2 beam) and (dose spac\$3 gap\$3 distance dosage)	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 10:01
L17	100	(proximity near2 effect) and (film resist photoresist) near7 (thick thickness height) and (e-beam electron near2 beam) and ((dose spac\$3 gap\$3 distance dosage) near4 (chosen adjust\$3 var\$3))	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 10:02
L18	27	(proximity near2 effect) and (film resist photoresist) near7 (thick thickness height) and (e-beam electron near2 beam) and (scatter backscatter) and ((dose spac\$3 gap\$3 distance dosage) near4 (chosen adjust\$3 var\$3))	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 10:17

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L19	54	(proximity near2 effect) and (film resist photoresist) near7 (thick thickness height) near7 (measur\$3 measurement) and (e-beam electron near2 beam)	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 11:24
L20	54	(US-20010018166-\$ or US-20020182541-\$ or US-20030130806-\$ or US-20040135101-\$ or US-20040152024-\$ or US-20040185354-\$ or US-20040233444-\$ or US-20040233443-\$ or US-20040233442-\$ or US-20040233441-\$ or US-20040233440-\$ or US-20040233439-\$ or US-20040257571-\$ or US-20050010890-\$ or US-20050196193-\$ or US-20050201660-\$ or US-20050200942-\$ or US-20050221225-\$ or US-20050227171-\$ or US-20050227170-\$ or US-20050275820-\$ or US-20060014003-\$ or US-20060057471-\$ or US-20060088787-\$ or US-20060121390-\$ or US-20060136862-\$).did. or (US-20060240355-\$).did. or (US-4409262-\$ or US-4430419-\$ or US-4551417-\$ or US-4564576-\$ or US-4954717-\$ or US-5087537-\$ or US-5242770-\$ or US-5393634-\$ or US-5489573-\$ or US-5736281-\$ or US-5783367-\$ or US-5994009-\$ or US-6033134-\$ or US-6107009-\$ or US-6146761-\$ or US-6200736-\$ or US-6511792-\$ or US-6542830-\$ or US-6603120-\$ or US-6653634-\$ or US-6757621-\$ or US-6794886-\$ or US-6900001-\$ or US-7008749-\$ or US-7049044-\$ or US-7053387-\$). did. or (US-7135344-\$).did.	US-PGPUB; USPAT	OR	ON	2007/01/03 10:23
L21	54	I20 and (proximity near2 effect) and (film resist photoresist) near7 (thick thickness height) near7 (measur\$3 measurement)	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 10:53

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L22	82	(proximity near2 effect) and (film resist photoresist) near7 (thick thickness height) near7 (measur\$3 measurement)	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 10:56
L23	28	I22 not I21	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 10:54
L24	205	(proximity near2 effect) and (DVD)	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 10:56
L25	4	(proximity near2 effect) and DVD and (film resist photoresist) near7 (thick thickness height) near7 (measur\$3 measurement)	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 10:57
L26	4	(proximity near2 effect) and DVD and (film resist photoresist) same (thick thickness height) same (measur\$3 measurement)	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 10:57
L27	75	(proximity near2 effect) and DVD and (film resist photoresist) same (thick thickness height measur\$3 measurement)	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 11:12
L28	3	(proximity near2 effect) and DVD and (diffraction near2 grating)	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 11:12
L29	8	(proximity near2 effect) and DVD and (diffraction and grating)	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 11:13
L30	1	10/789310	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 11:13
L31	0	I30 and (proximity near2 effect)	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 11:13
L32	0	I30 and (proximity near4 effect)	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 11:13
L33	0	I30 and (proximity and effect)	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 11:13
L34	184	(proximity adj effect) and (DVD)	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 11:14
L35	85	(proximity adj effect) and (DVD) and (e-beam electron near2 beam)	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 11:17

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L36	81	(proximity adj effect) and (DVD) and (e-beam electron near2 beam) and (film resist photoresist)	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 11:18
L37	81	(proximity adj effect) and (DVD) and (e-beam (electron near2 beam)) and (film resist photoresist)	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 11:18
L38	73	(proximity adj effect) and (DVD) and (film resist photoresist) same (error variable vary\$3 var\$3)	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 11:18
L39	35	(proximity adj effect) and (DVD) and (film resist photoresist) near7 (error variable vary\$3 var\$3)	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 11:19
L40	0	(proximity near2 effect) and (film resist photoresist) near7 (thick thickness height) near7 (measur\$3 measurement) and (e-beam electron near2 beam)	EPO; JPO	OR	ON	2007/01/03 11:24
L41	87	(film resist photoresist) near7 (thick thickness height) near7 (measur\$3 measurement) and (e-beam electron near2 beam)	EPO; JPO	OR	ON	2007/01/03 11:24
L42	5	(JP-10270338-\$ or JP-08161786-\$ or JP-04100205-\$ or JP-03173119-\$ or JP-02087616-\$).did.	JPO	OR	ON	2007/01/03 13:01
L43	10	(JP-10270338-\$ or JP-08161786-\$ or JP-04100205-\$ or JP-03173119-\$ or JP-02087616-\$).did.	JPO; DERWENT	OR	ON	2007/01/03 11:36
L44	2	"02087616" "63241463"	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 11:37
L45	19	(nozue and hiroshi).in.	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 11:38
L46	5	I45 and (film resist photoresist) same (thickness thick)	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 11:38
L47	19	(proximity adj effect) and (substrate wafer) near2 (curved)	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 13:01
L48	1274	(diffraction near2 gratings) same ((IC integrated near2 circuit) (semiconductor near2 device))	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 14:33
L49	714	(diffraction near2 gratings) with ((IC integrated near2 circuit) (semiconductor near2 device))	US-PGPUB; USPAT; USOCR	OR	ON	2007/01/03 14:33
L50	427	(diffraction near2 gratings) with ((integrated near2 circuit) (semiconductor near2 device))	USPAT	OR	ON	2007/01/03 14:34

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L51	424	(diffraction adj gratings) with ((integrated near2 circuit) (semiconductor near2 device))	USPAT	OR	ON	2007/01/03 14:34
L52	186	(diffraction adj gratings) with ((integrated adj circuit) (semiconductor adj device))	USPAT	OR	ON	2007/01/03 14:34
L53	7	(diffraction adj gratings) with ((integrated adj circuit) (semiconductor adj device)) same (e-beam electron)	USPAT	OR	ON	2007/01/03 14:37
L54	186	(diffraction adj.gratings) with ((integrated adj circuit) (semiconductor adj device))	USPAT	OR	ON	2007/01/03 14:38
L55	187	(diffraction adj gratings) with ((chip))	USPAT	OR	ON	2007/01/03 14:39
L56	6	(diffraction adj gratings) with ((chip) same (integrated near2 circuit))	USPAT	OR	ON	2007/01/03 14:42
L57	10	(e-beam) near4 (diffraction adj grating)	USPAT	OR	ON	2007/01/03 14:42
L60	1	(US-20030124442-\$).did.	US-PGPUB	OR	ON	2007/01/03 15:04
L61	1	I60 and (CD thickness critical measur\$3 measurement)	US-PGPUB	OR	ON	2007/01/03 15:05
L62	1	(US-6316163-\$).did.	USPAT	OR	ON	2007/01/03 15:20
L63	1	I62 and thickness	USPAT	OR	ON	2007/01/03 15:20

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S43	1	"6333572".pn.	US-PGPUB; USPAT	OR	ON	2006/07/13 09:03
S44	3	S41 S42 S43	US-PGPUB; USPAT	OR	ON	2006/07/13 09:03
S45	2	S44 and (height thickness)	US-PGPUB; USPAT	OR	ON	2006/07/13 09:03
S46	0	"6107637"".pn.19" and (height thickness measur\$3 measurement)	US-PGPUB; USPAT	OR	ON	2006/07/13 09:21
S47	0	"6107637"".pn." and (height thickness measur\$3 measurement)	US-PGPUB; USPAT	OR	ON	2006/07/13 09:21
S48	1	S36 and (height thickness measur\$3 measurement)	US-PGPUB; USPAT	OR	ON	2006/07/13 09:54
S49	1	"20020170887"	US-PGPUB; USPAT	OR	ON	2006/07/13 09:54
S50	1	S49 and (grating space)	US-PGPUB; USPAT	OR	ON	2006/07/13 10:31
S51	1	S49 and (film resist)	US-PGPUB; USPAT	OR	ON	2006/07/13 10:32
S52	1	S49 and (depict\$3 mode beam)	US-PGPUB; USPAT	OR	ON	2006/07/13 10:33
S53	1	S49 and (diffraction diffractive grating) same (mode electron beam)	US-PGPUB; USPAT	OR	ON	2006/07/13 10:35
S54	1	S49 and (dose) same (mode electron beam)	US-PGPUB; USPAT	OR	ON	2006/07/13 10:40
S55	1	S49 and (adjust adjustment)	US-PGPUB; USPAT	OR	ON	2006/07/13 10:41
S56	1	S49 and (adjust adjustment) same (space)	US-PGPUB; USPAT	OR	ON	2006/07/13 10:42
S57	1	S49 and (adjust adjustment) same (diffraction grating)	US-PGPUB; USPAT	OR	ON	2006/07/13 10:48
S58	6326	(laser near4 beam) same (depict\$3)	US-PGPUB; USPAT	OR	ON	2006/07/13 10:54
S59	1	S49 and error	US-PGPUB; USPAT; USOCR	OR	ON	2006/07/13 10:54
S60	0	(electron near4 beam) same (measuring or adjusting or measured or adjusted) same "diffraction."	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/12/21 15:56
S61	802	(electron near4 beam) same (measuring or adjusting or measured or adjusted) same diffraction	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/12/21 15:56

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S62	18	S61 and ("264"/).clas.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERVENT	OR	ON	2006/12/21 15:58
S63	34786	(diffraction near2 grating)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/12/21 15:59
S64	3150	(diffraction near2 grating) and (electron near2 beam)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/12/21 15:59
S65	255	(diffraction near2 grating) and (electron near2 beam) and (resist near2 film)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/12/21 15:59
S66	181	(diffraction near2 grating) and (electron near2 beam) and (resist near2 film) and (error measur\$3 measurement) and (height thickness error depth)	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/12/21 16:00
S67	136	(diffraction near2 grating) and (electron near2 beam) and (resist near2 film) and ((error measur\$3 measurement adjust adjust\$3 adjustment) with (height thickness error depth))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/12/21 16:01
S68	60	(diffraction near2 grating) and (electron near2 beam) and (resist near2 film) and ((error measur\$3 measurement adjust adjust\$3 adjustment) with (height thickness error depth) same (diffraction grating depict\$3))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/12/21 16:10
S69	39	(diffraction near2 grating) and (electron near2 beam) and (resist near2 film) and ((error measur\$3 measurement adjust adjust\$3 adjustment) with (height thickness error depth) same (diffraction grating depict\$3) same (resist film))	US-PGPUB; USPAT; USOCR; EPO; JPO	OR	ON	2006/12/21 16:10
S70	1	(JP-2004271857-\$).did.	JPO	OR	ON	2006/12/21 16:25
S71	2	(JP-2004271857-\$).did.	JPO; DERVENT	OR	ON	2006/12/21 16:26
S72	2	(JP-2004271857-\$).did.	EPO; JPO; DERVENT	OR	ON	2006/12/21 16:26
S73	1	"20040185354"	EPO; DERVENT	OR	ON	2006/12/30 12:54

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S74	1	S73 and (shape data)	EPO; DERWENT	OR	ON	2006/12/30 12:54
S75	1	S73 and (shape data)	US-PGPUB; USPAT; USOCR; EPO; DERWENT	OR	ON	2006/12/30 12:54
S76	1	"20040185354"	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 12:54
S77	1	S76 and (shape data)	US-PGPUB; USPAT; USOCR; EPO; DERWENT	OR	ON	2006/12/30 12:54
S78	1	S76 and (shape near2 data)	US-PGPUB; USPAT; USOCR; EPO; DERWENT	OR	ON	2006/12/30 12:55
S79	8	("4330175" "4798446" "5004673" "5161057" "5393634" "5801795" "5978140" "6100974").PN. OR ("6480333"). URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 13:14
S80	6	S79 and (film resist)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 13:15
S81	6	S79 and (film resist) same (thick thickness measur\$3 measurement adjust\$3 adjustment)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 13:22
S82	52	("4051271" "4330175" "4360585" "4530736" "4772539" "4797334" "4895790" "5051598" "5057397" "5104772" "5112724" "5241185").PN. OR ("5004673" "5393634" "5978140").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 13:22
S83	31	S82 and (film resist photoresist) same (thick thickness measur\$3 measurement adjust\$3 adjustment)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 13:23
S84	31	S82 and (film resist photoresist) same (thick thickness measur\$3 measurement)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 13:36

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S85	121	("1581659" "3154751" "3360323" "3384433" "3743378" "4056393" "4083254" "4214813" "4298803" "4330175" "4403151" "4415262" "4463265" "4486073" "4500790" "4508813" "4520269" "4552831" "4659650" "4671630" "4701766" "4715929" "4758305" "4762396" "4798446" "4806456" "4871232" "4890289" "4903271" "4912022" "4915486" "4916712" "4935334" "4938841" "4943729" "4952026" "5004673" "5035486" "5051598" "5111240" "5161057" "5208125" "5316640" "5393634" "5518863" "5538817" "5672450" "5706066" "5776638" "5801795" "5841496" "5978140" "5999368" "6100974" "6144430" "6285426" "6376131" "6433848").PN. OR ("5104772" "5241185" "5252434" "5728509" "6480333" "6534425" "6573959").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 13:36
S86	75	S85 and (film resist photoresist) same (thick thickness measur\$3 measurement)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 13:36
S87	4	S85 and (film resist photoresist) same (thick thickness measur\$3 measurement) same (adjust\$3 adjustment) and (electron e-beam EB)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 13:42
S88	45	S85 and (film resist photoresist) same (thick thickness measur\$3 measurement) and (electron e-beam EB)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 13:42
S89	4	S85 and (film resist photoresist) same (thick thickness measur\$3 measurement) same (adjust\$3 adjustment) and (electron near2 beam e-beam EB)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 13:52
S90	42	S85 and (film resist photoresist) same (thick thickness measur\$3 measurement) and (electron near2 beam e-beam EB)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 13:52
S91	4325	("264"/).clas. and (("430"/)".clas" ("359"/).clas.)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 13:56

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S92	230	S91 and (film resist photoresist) same (thick thickness measur\$3 measurement) and (electron near2 beam e-beam EB)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 13:52
S93	25	S91 and (film resist photoresist) same (thick thickness measur\$3 measurement) same (adjust\$3 adjustment) and (electron near2 beam e-beam EB)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 13:57
S94	2136	("264"/).clas. and ((("430"/).clas. ("359"/).clas.)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 13:57
S95	18	S94 and (film resist photoresist) same (thick thickness measur\$3 measurement) same (adjust\$3 adjustment) and (electron near2 beam e-beam EB)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 13:58
S96	10	S94 and (film resist photoresist) near7 (thick thickness measur\$3 measurement) same (adjust\$3 adjustment) and (electron near2 beam e-beam)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 13:59
S97	9688	(film resist photoresist) near7 (thick thickness measur\$3 measurement) same (electron near2 beam e-beam)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 13:59
S98	451	(film resist photoresist) near7 (thick thickness measur\$3 measurement) same (electron near2 beam e-beam) same (diffraction grating)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 14:00
S99	72	(film resist photoresist) near7 (thick thickness measur\$3 measurement) same (electron near2 beam e-beam) same (diffraction and grating)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 14:00
S100	20	(film resist photoresist) near7 (thick thickness measur\$3 measurement) same (electron near2 beam e-beam) same (diffraction and grating) same (adjust\$3 adjustment control\$3 controll\$3)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 14:08
S101	276	(film resist photoresist) near7 (thick thickness) near7 (measur\$3 measurement) and (electron near2 beam e-beam) and (diffraction and grating) and (adjust\$3 adjustment control\$3 controll\$3)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 14:09

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S10 2	195	(film resist photoresist) near7 (thick thickness) near7 (measur\$3 measurement) and (electron near2 beam e-beam) and (diffraction near7 grating) and (adjust\$3 adjustment control\$3 controll\$3)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 14:22
S10 3	61	(film resist photoresist) near7 (thick thickness) near7 (measur\$3 measurement) and ((electron near2 beam e-beam) same (adjust\$3 adjustment control\$3 controll\$3)) and (diffraction near7 grating)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 14:09
S10 4	61	(film resist photoresist) near7 (thick thickness) near7 (measur\$3 measurement) and ((electron near2 beam e-beam) same (adjust\$3 adjustment control\$3 controll\$3)) and (diffraction near7 grating)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 14:10
S10 5	69	(film resist photoresist) near7 (thick thickness) near7 (measur\$3 measurement) and (electron near2 beam e-beam) and (diffraction near7 grating) and (adjust\$3 adjustment control\$3 controll\$3) and (CD DVD)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 14:22
S10 6	8	(film resist photoresist) near7 (thick thickness) near7 (measur\$3 measurement) and (electron near2 beam e-beam) and (diffraction near7 grating) and (adjust\$3 adjustment control\$3 controll\$3) and (CD and DVD)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 14:25
S10 7	11	(film resist photoresist) near7 (thick thickness) near7 (measur\$3 measurement) and (electron near2 beam e-beam) and (diffraction near7 grating) and ("264"/).clas.	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 14:55
S10 8	1	(film resist photoresist) near7 (thick thickness) near7 (measur\$3 measurement) near7 (error) and (electron near2 beam e-beam) and (diffraction near7 grating) and ("264"/).clas.	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 14:28
S10 9	1	(film resist photoresist) near7 (thick thickness) near7 (measur\$3 measurement) near7 (error) and (electron near2 beam e-beam) and (diffraction near7 grating)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 14:31
S11 0	2973	(264/1.1,1.7,1.9,2.5,2.7,1.31,1.34, 1.36,1.37).ccls.	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 14:46

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S11 1	40	S110 and (film resist photoresist) near7 (thick thickness) near7 (measur\$3 measurement)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 14:31
S11 2	1	(US-6077349-\$).did.	USPAT	OR	ON	2006/12/30 14:40
S11 3	1	S112 and (electron beam e-beam)	USPAT	OR	ON	2006/12/30 14:40
S11 4	4	("6077349").URPN.	USPAT	OR	ON	2006/12/30 14:42
S11 5	0	S114 and (electron near2 beam e-beam)	USPAT	OR	ON	2006/12/30 14:42
S11 6	71	S110 and (CD and DVD)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 14:46
S11 7	15	S110 and (CD and DVD) and (electron near2 beam e-beam)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 14:46
S11 8	78	(film resist photoresist) near7 (thick thickness) near7 (measur\$3 measurement) and (spac\$3 gap distance pitch) near7 (diffraction near2 grating)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 14:55
S11 9	4	(2002/0170887)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/12/30 15:41
S12 0	2	("20020170887")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2006/12/30 15:41
S12 1	1	("20020170887")	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 15:41
S12 2	0	S121 and (thickness resist film) same (dose)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 15:41
S12 3	0	S121 and (thickness resist film) near7 (dose)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 15:41
S12 4	1	S121 and (thickness resist film) same (dose dosage electron near2 beam e-beam)	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/30 15:41